

STW55NM60ND

N-channel 600 V - 0.047 Ω - 51 A TO-247 FDmesh™ II Power MOSFET (with fast diode)

Preliminary Data

Features

Туре	V _{DSS}	R _{DS(on)}	I _D	Pw
STW55NM60ND	600 V	< 0.060 Ω	51 A	350 W

- The worldwide best R_{DS(on)} amongst the fast recovery diode devices in TO-247
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance
- High dv/dt and avalanche capabilities



Switching applications



The FDmesh™ II series belongs to the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a new vertical structure to the company's strip layout and associates all advantages of reduced onresistance and fast switching with an intrinsic fast-recovery body diode.It is therefore strongly recommended for bridge topologies, in particular ZVS phase-shift converters.

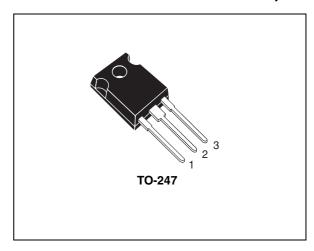


Figure 1. Internal schematic diagram

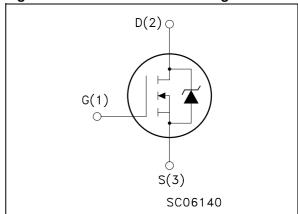


Table 1. Device summary

Order codes	Marking	Package	Packaging	
STW55NM60ND	55NM60ND	TO-247	Tube	

Electrical ratings STW55NM60ND

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	600	V
V _{GS}	Gate- source voltage	±25	V
I _D	Drain current (continuous) at T _C = 25 °C	51	Α
I _D	Drain current (continuous) at T _C = 100 °C	32	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	204	Α
P _{TOT}	Total dissipation at T _C = 25 °C	350	W
	Derating factor	2.8	W/°C
dv/dt ⁽²⁾	Peak diode recovery voltage slope	40	V/ns
T _{stg}	Storage temperature -55 to 150		°C
T _j	Max. operating junction temperature	150	

^{1.} Pulse width limited by safe operating area

Table 3. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max	0.36	°C/W
Rthj-amb	Thermal resistance junction-ambient max	50	°C/W
T _I	Maximum lead temperature for soldering purpose	300	°C

Table 4. Avalanche characteristics

Symbol	Parameter	Max value	Unit
I _{AS}	Avalanche current, repetitive or not- repetitive (pulse width limited by T_j max)	15	Α
E _{AS}	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AS}$, $V_{DD} = 50$ V)	850	mJ

^{2.} $I_{SD} \leq 51$ A, di/dt ≤ 600 A/ μ s, $V_{DD} = 80\%$ $V_{(BR)DSS}$

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating @125 °C			1 10	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 25.5 \text{ A}$		0.047	0.060	Ω

Table 6. Dynamic

Tubic o.	Bynamo					
Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15 V_{,} I_{D} = 25.5 A$		45		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 50 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$		5800 300 30		pF pF pF
Coss eq. (2)	Equivalent output capacitance	V _{GS} = 0, V _{DS} = 0 to 480 V		900		pF
t _{d(on)}	Turn-on delay time	V _{DD} = 300 V, I _D = 25.5 A		TBD		ns
t _r	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$		TBD		ns
t _{d(off)}	Turn-off delay time	(see Figure 7),		TBD		ns
t _f	Fall time	(see Figure 2)		TBD		ns
Q_{g}	Total gate charge	$V_{DD} = 480 \text{ V}, I_{D} = 51 \text{ A},$		190		nC
Q_{gs}	Gate-source charge	$V_{GS} = 10 \text{ V},$		30		nC
Q_{gd}	Gate-drain charge	(see Figure 3)		90		nC
R _g	Gate input resistance	f=1 MHz Gate DC Bias = 0 Test signal level = 20 mV Open drain		2.5		Ω

^{1.} Pulsed: pulse duration=300 μ s, duty cycle 1.5%

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^{2.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Electrical characteristics STW55NM60ND

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				51 204	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 50 A, V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 50 A, V_{DD} = 100 V di/dt = 100 A/µs (see Figure 4)		TBD TBD TBD		ns μC Α
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 50 A,V _{DD} = 100 V di/dt = 100 A/µs, T_j = 150 °C (see Figure 4)		TBD TBD TBD		ns μC A

^{1.} Pulse width limited by safe operating area

^{2.} Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%.

STW55NM60ND Test circuit

3 Test circuit

Figure 2. Switching times test circuit for resistive load

Figure 3. Gate charge test circuit

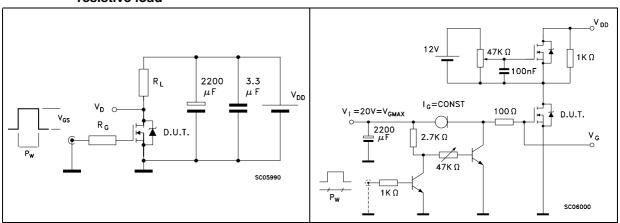


Figure 4. Test circuit for inductive load switching and diode recovery times

Figure 5. Unclamped Inductive load test circuit

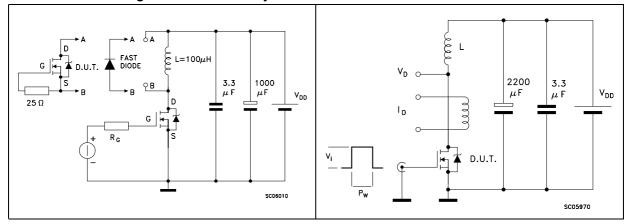
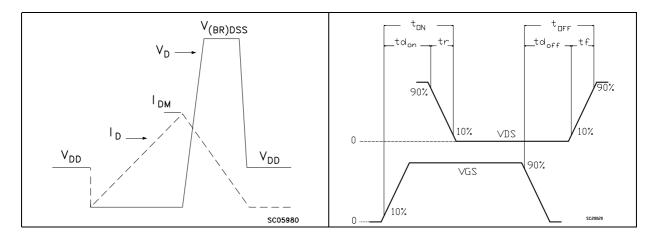


Figure 6. Unclamped inductive waveform

Figure 7. Switching time waveform



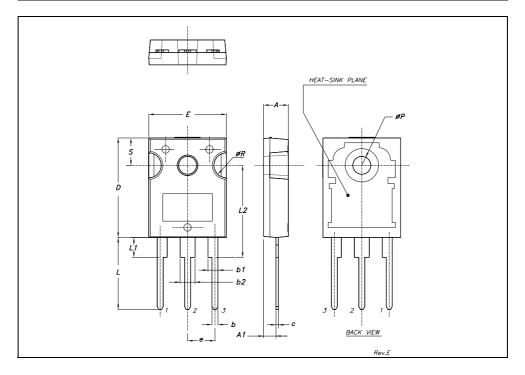
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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com.

TO-247 MECHANICAL DATA

DIM.		mm.			inch	
DIWI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.85		5.15	0.19		0.20
A1	2.20		2.60	0.086		0.102
b	1.0		1.40	0.039		0.055
b1	2.0		2.40	0.079		0.094
b2	3.0		3.40	0.118		0.134
С	0.40		0.80	0.015		0.03
D	19.85		20.15	0.781		0.793
Е	15.45		15.75	0.608		0.620
е		5.45			0.214	
L	14.20		14.80	0.560		0.582
L1	3.70		4.30	0.14		0.17
L2		18.50			0.728	
øΡ	3.55		3.65	0.140		0.143
øR	4.50		5.50	0.177		0.216
S		5.50			0.216	



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Revision history STW55NM60ND

5 Revision history

Table 8. Document revision history

Date	Revision	Changes
16-Nov-2007	1	First release.

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